

Supporting Information

Sequential monitoring of elemental mercury in stack gas by dielectric barrier discharge micro-plasma emission spectrometry

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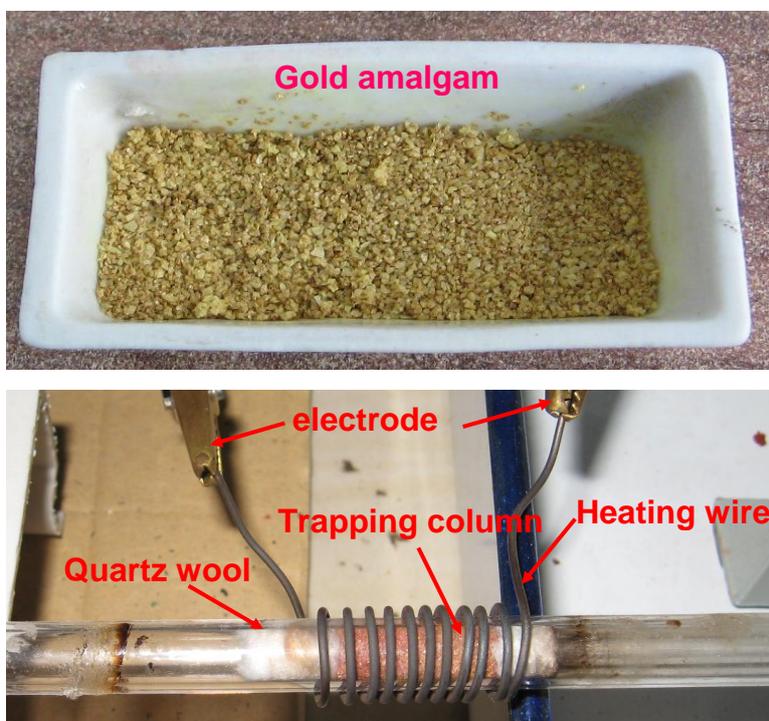


Fig. S1. Upper: the gold amalgam; Bottom: the gold amalgam trapping micro-column.

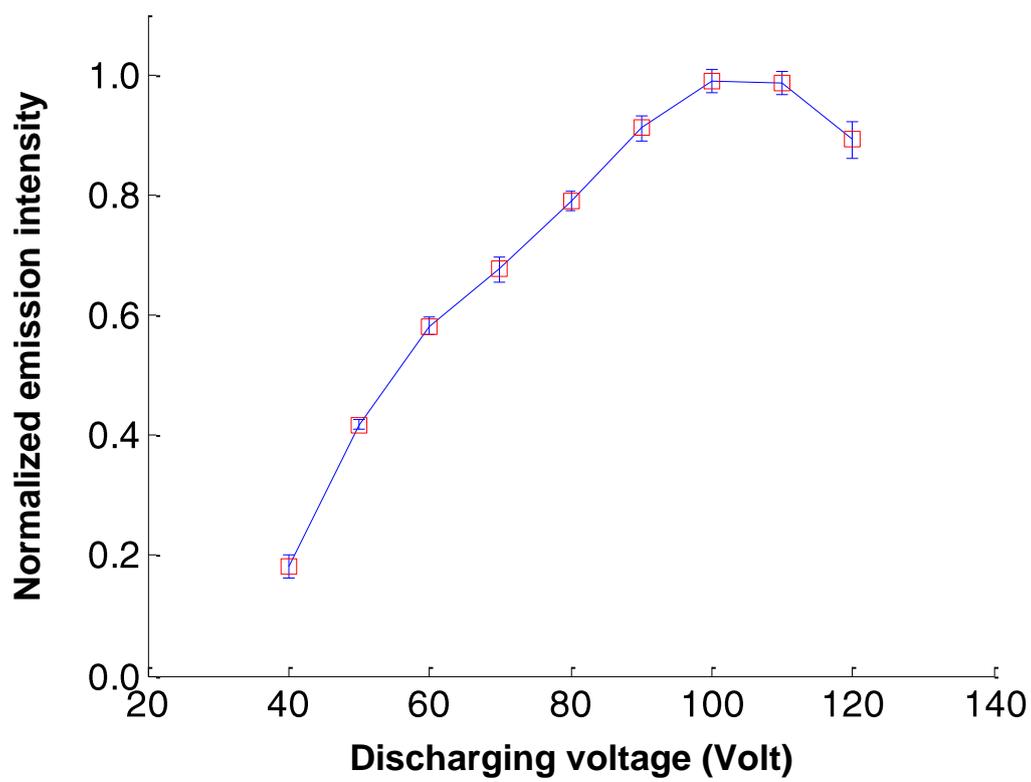


Fig. S2. The variation of normalized emission intensity at 253.7 nm with the discharging voltage. Flow rate: 0.6 L min^{-1} , discharge frequency: 43 KHz, Hg^0 vapor concentration: 0.30 ppb.

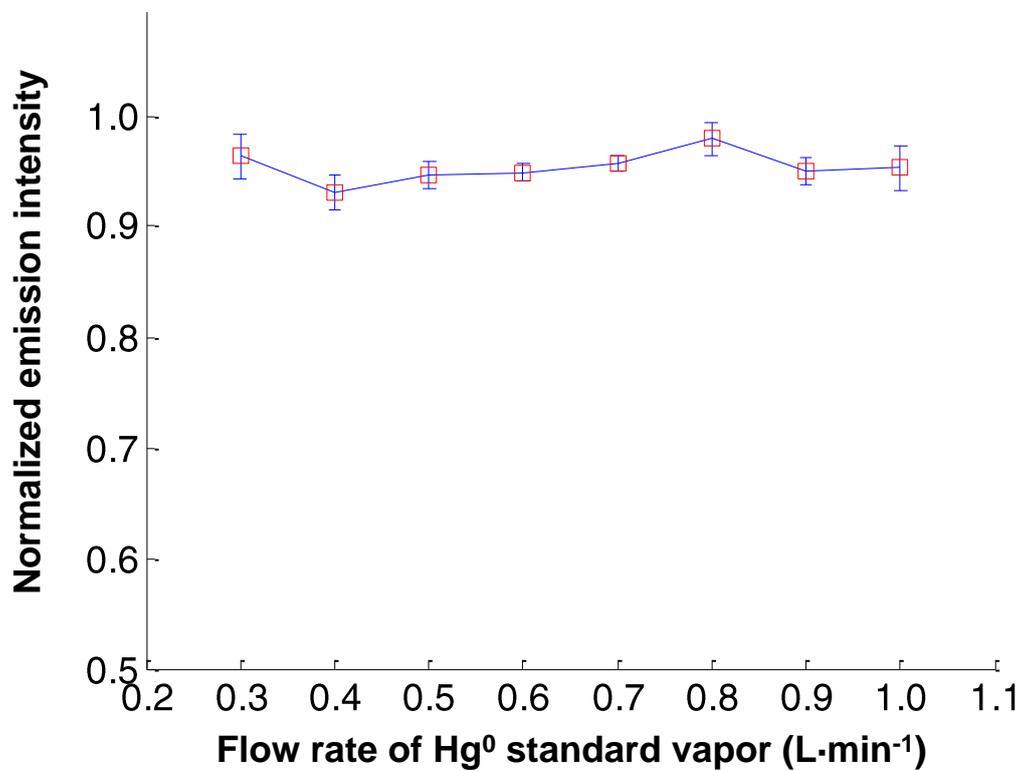


Fig. S3. The dependence of the normalized Hg⁰ emission intensity at 253.7 nm on the flow rate of the carrier gas. The discharging voltage: 100 V; discharge frequency: 43 KHz, the concentration of Hg⁰ in the standard vapor: 0.30 ppb.